SN54ABT5402A, SN74ABT5402A 12-BIT LINE/MEMORY DRIVERS WITH 3-STATE OUTPUTS

SCBS660B - FEBRUARY 1996 - REVISED MAY 1997

- Output Ports Have Equivalent 25-Ω Series Resistors, So No External Resistors Are Required
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V_{OLP} (Output Ground Bounce) < 1 V at V_{CC} = 5 V, T_A = 25°C
- Typical V_{OLV} (Output Undershoot) < 0.5 V at V_{CC} = 5 V, T_A = 25°C
- Package Options Include Plastic Small-Outline (DW) Package and Ceramic Chip Carriers (FK) and DIPs (JT)

description

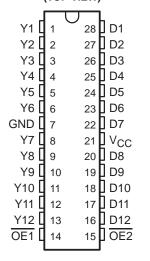
These 12-bit buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output-enable (OE1 or OE2) input is high, all 12 outputs are in the high-impedance state.

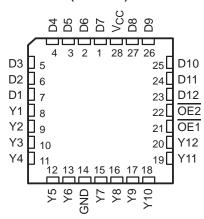
The outputs, which are designed to source or sink up to 12 mA, include equivalent 25- Ω series resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

SN54ABT5402A . . . JT PACKAGE SN74ABT5402A . . . DW PACKAGE (TOP VIEW)



SN54ABT5402A . . . FK PACKAGE (TOP VIEW)



The SN54ABT5402A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABT5402A is characterized for operation from –40°C to 85°C.

FUNCTION TABLE

	INPUTS	ОИТРИТ	
OE1	OE2	D	Y
L	L	L	L
L	L	Н	Н
Н	X	Χ	Z
X	Н	Χ	Z



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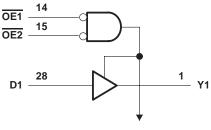
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logic symbol†

OE1 15 ΕN OE2 28 D1 ∇ **Y1** 2 27 **Y2** D2 3 26 Υ3 D3 25 4 D4 **Y4** 24 5 D5 Y5 6 23 D6 Υ6 8 22 D7 **Y7** 20 9 D8 Y8 19 10 D9 Y9 18 11 Y10 D10 17 12 D11 Y11 16 13 D12 Y12

logic diagram (positive logic)



To Eleven Other Channels

Pin numbers shown are for the DW and JT packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}	
Input voltage range, V _I (see Note 1)	0.5 V to 7 V
Voltage range applied to any output in the high or power-off state, VO	
Current into any output in the low state, I _O	30 mA
Input clamp current, I _{IK} (V _I < 0)	–18 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Package thermal impedance, θ_{JA} (see Note 2): DW package	78°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 - 2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

recommended operating conditions (see Note 3)

				SN54ABT5402A		SN74ABT5402A	
			MIN	MAX	MIN	MAX	UNIT
V _{CC} Supply voltage				5.5	4.5	5.5	V
V _{IH} High-level input voltage				EW	2		V
VIL	V _{IL} Low-level input voltage			0.8		0.8	V
VI	V _I Input voltage			Vcc	0	VCC	V
IOH	IOH High-level output current			-12		-12	mA
loL	OL Low-level output current		200	12		12	mA
Δt/Δν	Input transition rise or fall rate	Outputs enabled	32	10		10	ns/V
T _A	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		T _A = 25°C			SN54ABT5402A		SN74ABT5402A		
PAR	TANAMETER		DITIONS	MIN	TYP [†]	MAX	MIN	MAX	MIN	MAX	UNIT
VIK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2		-1.2		-1.2	V
	Voн	V _{CC} = 4.5 V,	$I_{OH} = -1 \text{ mA}$	3.35	3.7		3.3		3.35		
Vou		$V_{CC} = 5 V$,	I _{OH} = -1 mA	3.85	4.2		3.8		3.85		V
VOH		V _{CC} = 4.5 V	$I_{OH} = -3 \text{ mA}$				3		3.1		
			$I_{OH} = -12 \text{ mA}$	2.6					2.6		
VOL		V _{CC} = 4.5 V	$I_{OL} = 8 \text{ mA}$					0.8		0.65	V
VOL		VCC = 4.5 V	I_{OL} = 12 mA							0.8	
V _{hys}					100						mV
$V_{CC} = 5.5 \text{ V}, V_{I} = V_{C}$		CC or GND			±1		±1		±1	μΑ	
lozh		$V_{CC} = 5.5 \text{ V},$	$V_0 = 2.7 \text{ V}$			10		_10		10	μΑ
lozL		$V_{CC} = 5.5 \text{ V},$	$V_0 = 0.5 V$			-10		-10		-10	μΑ
l _{off}		$V_{CC} = 0$,	V_I or $V_O \le 4.5 \text{ V}$			±100	4	24		±100	μΑ
ICEX		V _{CC} = 5.5 V, V _O = 5.5 V	Outputs high			50	202	50		50	μΑ
Io		$V_{CC} = 5.5 \text{ V},$	V _O = 2.5 V	-25	-45	-100	25	-100	-25	-100	mA
los [‡]		V _{CC} = 5.5 V,	V _O = 0	-50		-200	- 50	-200	-50	-200	mA
		V _{CC} = 5.5 V,	Outputs high		5	50		50		50	μΑ
Icc		$I_{O} = 0$,	Outputs low		39	48		48		48	mA
		$V_I = V_{CC}$ or GND	Outputs disabled		1	50		50		50	μΑ
	Data inputs	V _{CC} = 5.5 V, One input at 3.4 V,	Outputs enabled			1.5		1.5		1.5	
ΔI _{CC} §		Other inputs at V _{CC} or GND	Outputs disabled			0.05		0.05		0.05	mA
	Control inputs	V _{CC} = 5.5 V, One input at 3.4 V, Other inputs at V _{CC} or GND				1.5		1.5		1.5	
C _i	C _i V _I = 2.5 V or 0.5 V			3						pF	
Co		V _O = 2.5 V or 0.5 V			8						pF

[†] All typical values are at $V_{CC} = 5 \text{ V}$.

[§] This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



[‡] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

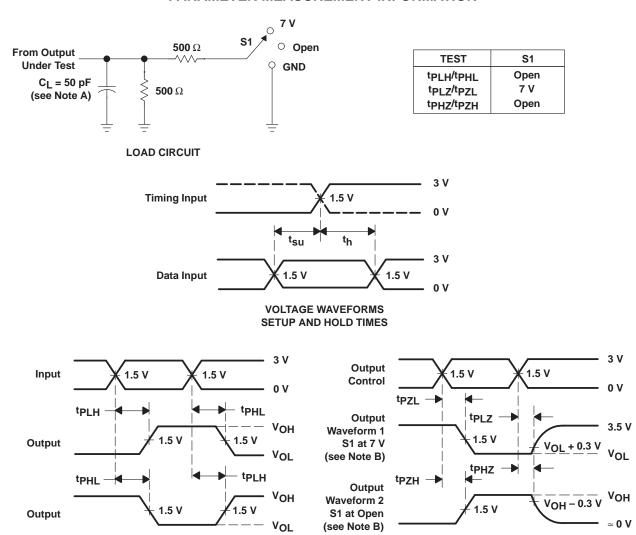
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, T _A = 25°C			SN54ABT5402A		SN74ABT5402A		UNIT
	(INFOT)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	1 1
^t PLH	D	Y	2	4.5	5.2	2	6.3	2	6.2	ns
^t PHL			1.5	3.7	5	1.5	5.7	1.5	5.6	
^t PZH	ŌĒ	Y	2.5	5.7	7.6	2.5	8.8	2.5	8.7	ns
^t PZL			2	4.4	6.3	3	7.6	2	7.5	
^t PHZ	ŌĒ	V	1.5	3.6	4.4	01.5	5.5	1.5	5.2	ns
t _{PLZ}		OE Y	1.5	4.2	5.4	1.5	7.4	1.5	6.9	

VOLTAGE WAVEFORMS

ENABLE AND DISABLE TIMES

LOW- AND HIGH-LEVEL ENABLING

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

VOLTAGE WAVEFORMS

PROPAGATION DELAY TIMES

INVERTING AND NONINVERTING OUTPUTS

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , $t_{\rm f} \leq$ 2.5 ns, $t_{\rm f} \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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